查询TLC7628供应商

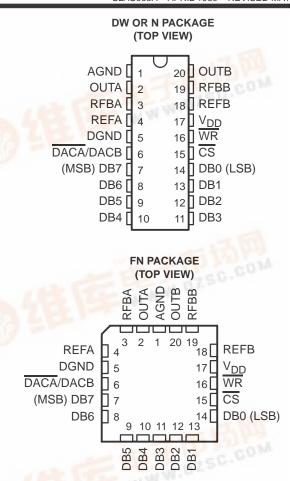
多邦,专业PCFLC7628C4小LC7628E,TLC7628I DUAL 8-BIT MULTIPLYING DIGITAL-TO-ANALOG CONVERTERS SLAS063A - APRIL 1989 - REVISED MAY 1995

- Easy Microprocessor Interface
- On-Chip Data Latches
- Digital Inputs Are TTL-Compatible With 10.8-V to 15.75-V Power Supply
- Monotonic Over the Entire A/D Conversion Range
- Fast Control Signaling for Digital Signal Processor (DSP) Applications Including Interface With TMS320
- CMOS Technology

KEY PERFORMANCE SPECIFICATIONS					
Resolution	8 bits				
Linearity Error	1/2 LSB				
Power Dissipation	20 mW				
Settling Time	100 ns				
Propagation Delay Time	80 ns				

description

The TLC7628C, TLC7628E, and TLC7628I are dual, 8-bit, digital-to-analog converters (DACs) designed with separate on-chip data latches and feature exceptionally close DAC-to-DAC matching. Data is transferred to either of the two DAC data latches through a common, 8-bit input port. Control input DACA/DACB determines which DAC is loaded. The load cycle of these devices is similar to the write cycle of a random-access memory, allowing easy interface



to most popular microprocessor buses and output ports. Segmenting the high-order bits minimizes glitches during changes in the most significant bits, where glitch impulse is typically the strongest.

The TLC7628C operates from a 10.8-V to 15.75-V power supply and is TTL-compatible over this range. 2- or 4-quadrant multiplying makes these devices a sound choice for many microprocessor-controlled gain-setting and signal-control applications.

The TLC7628C is characterized for operation from 0°C to 70°C. The TLC7628I is characterized for operation from –25°C to 85°C. The TLC7628E is characterized for operation from –40°C to 85°C.

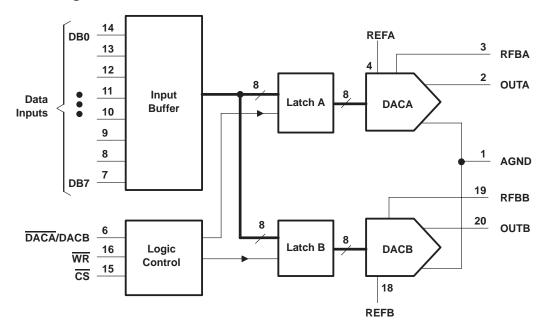
AVAILABLE OPTIONS						
		PACKAGE	A M M M			
TA	SMALL OUTLINE PLASTIC DIP (DW)	PLASTIC CHIP CARRIER (FN)	PLASTIC DIP (N)			
0°C to 70°C	TLC7628CDW	TLC7628CFN	TLC7628CN			
-25°C to 85°C	TLC7628IDW	TLC7628IFN	TLC7628IN			
-40°C to 85°C	TLC7628EDW	TLC7628EFN	TLC7628EN			



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



functional block diagram



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{DD} (to AGND or DGND)	
Voltage between AGND and DGND	V _{DD}
Input voltage range, V _I (to DGND)	$\dots \dots \dots -0.3 \text{ V to V}_{\text{DD}} + 0.3 \text{ V}$
Reference voltage range, V _{refA} or V _{refB} (to AGND)	±25 V
Feedback voltage range, V _{RFBA} or V _{RFBB} (to AGND)	
Output voltage range, V _{OA} or V _{OB} (to AGND)	±25 V
Peak input current	
Operating free-air temperature range, T _A : TLC7628C	0°C to 70°C
TLC7628I	–25°C to 85°C
TLC7628E	–40°C to 85°C
Storage temperature range, T _{stg}	
Case temperature for 10 seconds, T _C : FN package	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: DW or N p	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



recommended operating conditions

			MIN	NOM	MAX	UNIT
Supply voltage, V _{DD}			10.8		15.75	V
Reference voltage, V _{refA} or V _{refB}				±10		V
High-level input voltage, VIH			2.4			V
Low-level input voltage, VIL					0.8	V
CS setup time, t _{SU(CS)}			50			ns
CS hold time, th(CS) (see Figure 1)			0			ns
DAC select setup time, t _{SU(DAC)} (see Figure 1)			60			ns
DAC select hold time, t _{h(DAC)} (see Figure 1)			10			ns
Data bus input setup time t _{su(D)} (see Figure 1)			25			ns
Data bus input hold time th(D) (see Figure 1)			10			ns
Pulse duration, $\overline{\text{WR}}$ low, $t_{W(WR)}$ (see Fig	ure 1)		50			ns
	TLC7628C		0		70	
Operating free-air temperature, TA	TLC7628I		-25		85	°C
	TLC7628E		-40		85	

electrical characteristics over recommended ranges of operating free-air temperature and V_{DD} , $V_{refA} = V_{refB} = 10 V$, V_{OA} and V_{OB} at 0 V (unless otherwise noted)

PARAMETER			TEST CONDITIONS		MIN	MAX	UNIT	
1				Full range		10		
I _{IH} High-level input current		$V_{I} = V_{DD}$	25°C		1	μA		
1	Low lovel input ourrest		<u>)/: - 0</u>	Full range		-10	μA	
ΊL	Low-level input current		$V_{I} = 0$	25°C		-1	μΑ	
	Reference input impedance RI AGND	EFA or REFB to			5	20	kΩ	
		OUTA	DAC data latch loaded with 00000000,	Full range		±200		
1.		OUTA	$V_{refA} = \pm 10 V$	25°C		±50	nA	
l _{kg}	Output leakage current	OUTB	DAC data latch loaded with 00000000,	Full range		±200		
		0018	$V_{refB} = \pm 10 V$	25°C		±50		
	Input resistance match (REFA to REFB)					±1%		
			ΔVD = ± 5 %	Full range		0.02	%/%	
			$\nabla A D D = \pm 2.1\%$	25°C		0.01	70/70	
		Quiescent	All digital inputs at VIHmin or VILmax			2		
IDD	Supply current	Standby		Full range		0.5	mA	
		Standby	All digital inputs at 0 V or V_{DD}	25°C		0.1		
	Input capacitance DB0-DB7 WR, CS, DACA/DACB					10		
Ci						15	pF	
C	Output capacitance (OUTA, OUTB)		DAC data latches loaded with 00000000			25	pF	
Co			DAC data latches loaded with 11111111			60	рг	



operating characteristics over recommended ranges of operating free-air temperature and V_{DD} , $V_{refA} = V_{refB} = 10 \text{ V}$, V_{OA} and V_{OB} at 0 V (unless otherwise noted)

PARAN	IETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
Linearity error						±1/2	LSB
Settling time (to 1/2 L	_SB)	See Note 1	See Note 1			100	ns
Coin error		See Note 2	Full range			±3	LSB
Gain error		See Note 2	25°C			±2	
	REFA to OUTA	Cas Nata 2	Full range			-65	dB
AC feedthrough	REFB to OUTB	See Note 3	25°C			-75	aв
Temperature coefficient of gain		·				±0.0035	%FSR/°C
Propagation delay (fr 90% of final analog c	0 1	See Note 4				80	ns
Channel-to-channel	REFA to OUTB	See Note 5	25°C		80		dB
isolation	REFB to OUTA	See Note 6	25°C		80		uв
Digital-to-analog glitch impulse area $ \begin{array}{l} \mbox{Measured for code transition from 00000000 to 1111111,} \\ T_{A} = 25^{\circ} \mbox{C} \end{array} $			330		nV∙s		
Digital crosstalk		Measured for code transition from 00000000 to 11111111, $T_{\mbox{\scriptsize A}}$ = 25°C			60		nV∙s
Harmonic distortion		$V_i = 6 V$, $f = 1 kHz$, $T_A = 25^{\circ}C$			-85		dB

NOTES: 1. OUTA, OUTB load = 100 Ω , C_{ext} = 13 pF; \overline{WR} and \overline{CS} at 0 V; DB0–DB7 at 0 V to V_{DD} or V_{DD} to 0 V.

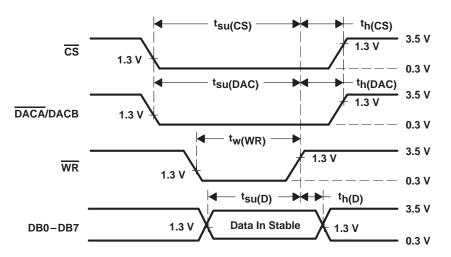
 Gain error is measured using an internal feedback resistor. Nominal full scale range (FSR) = V_{ref} – 1 LSB. Both DAC latches are loaded with 11111111.

3. V_{ref} = 20 V peak-to-peak, 10-kHz sine wave

4. $V_{refA} = V_{refB} = 10 \text{ V}$; OUTA/OUTB load = 100 Ω , $C_{ext} = 13 \text{ pF}$; \overline{WR} and \overline{CS} at 0 V; DB0–DB7 at 0 V to V_{DD} or V_{DD} to 0 V.

5. $V_{refA} = 20 V \text{ peak-to-peak}, 10\text{-kHz sine wave}; V_{refB} = 0$

6. VrefB = 20 V peak-to-peak, 10-kHz sine wave; VrefA = 0



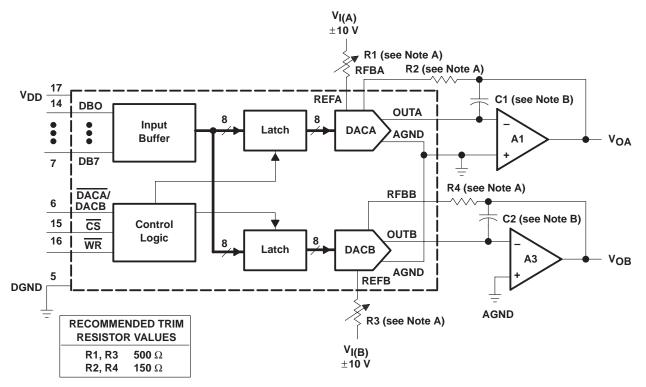
For all input signals, $t_f = t_f = 5$ ns (10% to 90% points).





APPLICATION INFORMATION

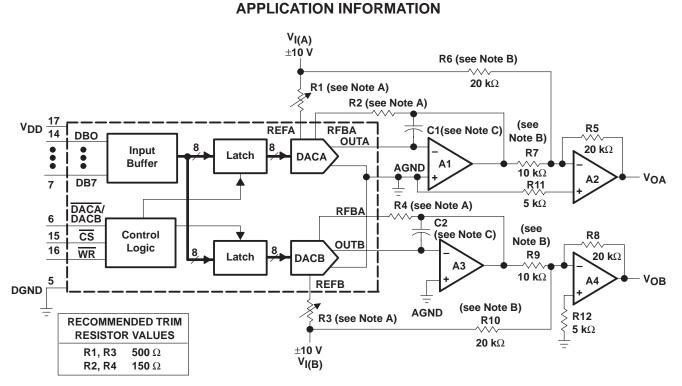
These devices are capable of performing 2-quadrant or full 4-quadrant multiplication. Circuit configurations for 2-quadrant and 4-quadrant multiplication are shown in Figures 2 and 3. Input coding for unipolar and bipolar operation are summarized in Tables 2 and 3, respectively.



- NOTES: A. R1, R2, R3, and R4 are used only if gain adjustment is required. See table for recommended values. Make gain adjustment with digital input of 255.
 - B. C1 and C2 phase compensation capacitors (10 pF to 15 pF) are required when using high-speed amplifiers to prevent ringing or oscillation.

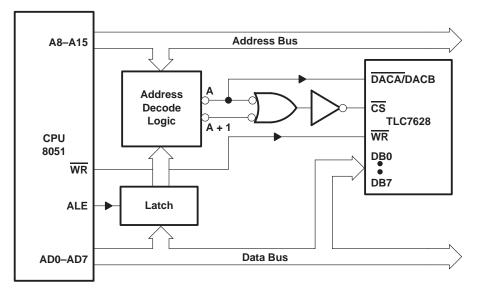
Figure 2. Unipolar Operation (2-Quadrant Multiplication)





- NOTES: A. R1, R2, R3, and R4 are used only if gain adjustment is required. See table for recommended values. Adjust R1 for V_{OA} = 0 V with code 10000000 in DACA latch. Adjust R3 for V_{OB} = 0 V with 10000000 in DACB latch.
 - B. Matching and tracking are essential for resistor pairs R6, R7, R9, and R10.
 - C. C1 and C2 phase compensation capacitors (10 pF to 15 pF) may be required if A1 and A3 are high-speed amplifiers.

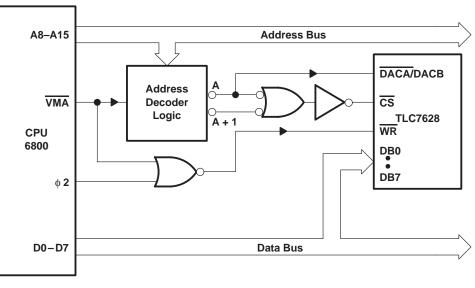
Figure 3. Bipolar Operation (4-Quadrant Operation)



NOTE D: A = decoded address for TLC7628 DACA A + 1 = decoded address for TLC7628 DACB

Figure 4. TLC7628 — Intel 8051 Interface





APPLICATION INFORMATION

NOTE D: A = decoded address for TLC7628 DACA A + 1 = decoded address for TLC7628 DACB

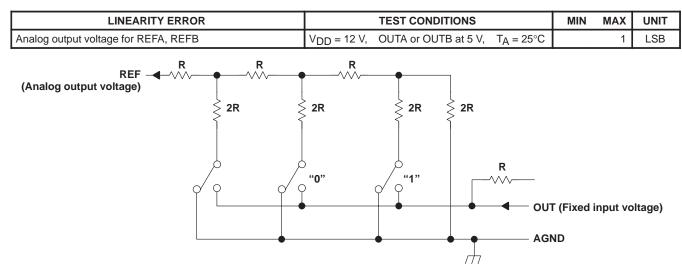
Figure 5. TLC7628 – 6800 Interface

voltage-mode operation

The current-multiplying DAC in these devices can be operated in a voltage mode. In the voltage mode, a fixed voltage is placed on the current output terminal. The analog output voltage is then available at the reference voltage terminal. An example of a current-multiplying DAC operating in voltage mode is shown in Figure 6. The relationship between the fixed input voltage and the analog output voltage is given by the following equation:

Analog output voltage = fixed input voltage (D/256)

where D = the digital input. In voltage-mode operation, these devices meet the following specification:





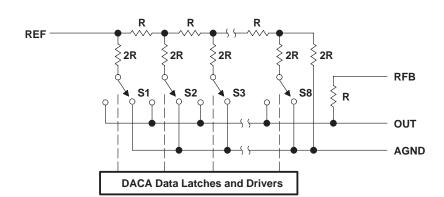


PRINCIPLES OF OPERATION

These devices contain two, identical, 8-bit, multiplying DACs: DACA and DACB. Each DAC consists of an inverted R-2R ladder, analog switches, and input data latches. Binary-weighted currents are switched between the DAC output and AGND, thus maintaining a constant current in each ladder leg independent of the switch state. Most applications require only the addition of an external operational amplifier and voltage reference. A simplified D/A circuit for DACA or DACB with all digital inputs low is shown in Figure 7.

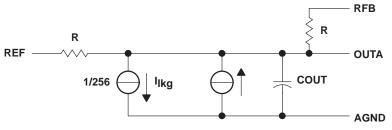
Figure 8 shows the DACA or DACB equivalent circuit. Both DACs share the analog ground terminal 1 (AGND). With all digital inputs high, the reference current flows to OUTA. A small leakage current (IIkg) flows across internal junctions, and as with most semiconductor devices, doubles every 10°C. The Co is caused by the parallel combination of the NMOS switches and has a value that depends on the number of switches connected to the output. The range of Co is 25 pF to 60 pF maximum. The equivalent output resistance (ro) varies with the input code from 0.8R to 3R where R is the nominal value of the ladder resistor in the R-2R network.

These devices interface to a microprocessor through the data bus, \overline{CS} , \overline{WR} , and $\overline{DACA}/DACB$ control signals. When CS and WR are both low, the analog output on these devices, specified by the DACA/DACB control line, responds to the activity on the DB0-DB7 data bus inputs. In this mode, the input latches are transparent and input data directly affects the analog output. When either the CS signal or WR signal goes high, the data on the DB0–DB7 inputs is latched until the CS and WR signals go low again. When CS is high, the data inputs are disabled, regardless of the state of the \overline{WR} signal.



The digital inputs of these devices provide TTL compatibility when operated from a supply voltage of 10.8 V to 15.75 V.

Figure 7. Simplified Functional Circuit for DACA or DACB



Latch A or Latch B Loaded With 1111111

Figure 8. TLC7628 Equivalent Circuit for DACA or DACB



PRINCIPLES OF OPERATION

Table 1. Mode Selection Table

DACA/DACB	CS	WR	DACA	DACB
L	L	L	Write	Hold
н	L	L	Hold	Write
Х	н	Х	Hold	Hold
Х	Х	Н	Hold	Hold

L = low level, H = high level, X = don't care

Table 2. Unipolar Binary Code

DAC LATCH CONTENTS (see Note 7)	ANALOG OUTPUT
MSB LSB	
11111111	–VI (255/256)
1000001	–V _I (129/256)
1000000	$-V_{i}$ (128/256) = $-V_{i}/2$
0111111	−V _I (127/256)
0000001	−V _I (1/256)
0 0 0 0 0 0 0 0	$-V_{I}(0/256) = 0$

Table 3. Bipolar (Offset Binary) Code

DAC LATCH CONTENTS (see Note 8)	ANALOG OUTPUT
MSB LSB	
11111111	V _I (127/128)
1000001	V _I (1/128)
1000000	0 V
01111111	−V _I (1/128)
0000001	−V _I (127/128)
0000000	–VI (128/128)

NOTES: 7. 1 LSB = $(2^{-8})V_I$ 8. 1 LSB = $(2^{-7})V_I$



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated